


<b>Search Notes</b>  	<b>Application/Control No.</b>  09329557	<b>Applicant(s)/Patent Under Reexamination</b>  HEINRICH ET AL.
	<b>Examiner</b>  Phu K Nguyen	<b>Art Unit</b>  2628

### SEARCHED

Class	Subclass	Date	Examiner
345	419, 420, 421, 422, 619, 620, 629, 630	11/20/08	pn
update	searches	6/18/09	pn
345	530, 543, 556	6/18/09	pn

### SEARCH NOTES

Search Notes	Date	Examiner
WEST search: stochastic sampling, supersampling, subpixel, sampling pattern, Poisson, distribution	11/20/08	pn
NonPatent Literature: IEEE, ACM, Google	11/20/08	pn
Inventor Name search	11/20/08	pn
Update searches	6/18/09	pn
Interference searches on Pre-Published Documents on WEST	6/18/09	pn

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
345	419, 422, 530, 543	6/18/09	pn

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